

4/30/03

INFORMATION DISCLOSURE CITATION

Atty. Docket No. 04329.3155	Serial No. Not Yet Assigned 10-673427
Applicants Kazuya FUKUHARA et al.	
Filing Date September 30, 2003	Group: Not Yet Assigned

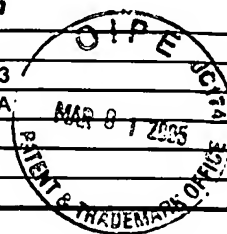
U.S. PATENT DOCUMENTS							
Examiner Initial*		Document Number	Issue Date	Name	Class	Sub Class	Filing Date If Appropriate

FOREIGN PATENT DOCUMENTS							
		Document Number	Publication Date	Country	Class	Sub Class	Translation Yes or No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)	
BB	SATO, K. et al., "Method For Inspecting Exposure Apparatus", U.S. Application No. 09/783,295, filed on February 15, 2001.
BB	SATO, K. et al., "Measuring Method of Illuminance Unevenness of Exposure Apparatus, Correcting Method of Illuminance Unevenness, Manufacturing Method of Semiconductor Device, and Exposure Apparatus", U.S. Patent Application No. 10/131,083, filed on April 25, 2002.

Examiner <i>Bryan Brown</i>	Date Considered 3/6/06
*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	
Form PTO 1449 Patent and Trademark Office - U.S. Department of Commerce	

IDS Form PTO/SB/08: Substitute for form 1449A/PTO				Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Application Number	10/673,427
				Filing Date	September 30, 2003
				First Named Inventor	Kazuya FUKUHARA
				Art Unit	2825
				Examiner Name	Unknown
Sheet	1	of	1	Attorney Docket Number	04329.3155



U.S. PATENTS AND PUBLISHED U.S. PATENT APPLICATIONS					
Examiner Initials	Cite No. ¹	Document Number	Issue or Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			

Note: Copies of the U.S. Patent Documents are not Required in IDS filed after October 21, 2004

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Translation ⁶
		Country Code ³ Number ⁴ Kind Code ⁵ (if known)				
		JP 11-184064	07/09/1999			No
		JP 2001-183811	07/06/2001			No

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	Translation ⁶
BB		Notification of Reasons for Rejection in First Examination issued by the Taiwanese Patent Office in counterpart Taiwanese application, and English translation of Notice	Yes

Examiner Signature	<i>[Signature]</i>	Date Considered	3/6/06
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

INFORMATION DISCLOSURE CITATION

Atty. Docket No. 4329.3155	Appln. No. 10/673,427
Applicant Fukuhara et al.	
Filing Date September 30, 2003	Group: 2825



U.S. PATENT DOCUMENTS							
Examiner Initial*		Document Number	Issue Date	Name	Class	Sub Class	Filing Date If Appropriate

FOREIGN PATENT DOCUMENTS							
		Document Number	Publication Date	Country	Class	Sub Class	Translation Yes or No
		2001-230170	8/24/01	Japan			
		9-63943	3/7/97	Japan			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)	

Examiner <i>Brian Brown</i>	Date Considered 3/6/06
*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	
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